



UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

WARREN M. FARNWORTH
ALAN G. WOOD
TRUNG TRI DOAN
DAVID R. HEMBREE

Art Unit: 2829

Serial No.: 08/838,452

Filing Date: 04/07/1997

Examiner: Karlsen, E.

Title: TEST APPARATUS FOR TESTING
SEMICONDUCTOR DICE INCLUDING
SUBSTRATE WITH PENETRATION
LIMITING CONTACTS FOR MAKING
ELECTRICAL CONNECTIONS
(AS AMENDED)

Attorney Docket No.: 91-62.17

*Entered Formal
Matters Only
E.P.K.
10-1-04*

**RESPONSE AFTER NOTICE OF ALLOWANCE
UNDER C.F.R. §1.312**

July 12, 2004

Mail Stop Issue Fee
Commissioner For Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

This Response is being filed after the Notice Of Allowance mailed 07/07/2004. The Notice Of Allowance lists the title as "Bondpad Attachments Having Self-Limiting Properties For Penetration Of Semiconductor Die". However, by the Amendment dated 11/11/1998 the title was changed to "Test Apparatus For Testing Semiconductor Dice Including Substrate With Penetration Limiting Contacts For Making Electrical Connections".